

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,810	CHANG ET AL.
Examiner	Art Unit
Hana A. Sanei	2879

	SEARCHED					
Class	Subclass	Date	Examiner			
445	23,24,25	7/26/2005	H.S.			
156	153,154	7/26/2005	H.S.			
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
For Text Search see attached "Search History	7/26/2005	H.S.
Consulted Jeff Aftergut for search	7/26/2005	H.S.
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